

IR2117(S)/IR2118(S) & (PbF)

SINGLE CHANNEL DRIVER

Features

- Floating channel designed for bootstrap operation
Fully operational to +600V
Tolerant to negative transient voltage
dV/dt immune
- Gate drive supply range from 10 to 20V
- Undervoltage lockout
- CMOS Schmitt-triggered inputs with pull-down
- Output in phase with input (IR2117) or out of phase with input (IR2118)
- Also available LEAD-FREE

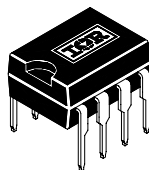
Description

The IR2117/IR2118(S) is a high voltage, high speed power MOSFET and IGBT driver. Proprietary HVIC and latch immune CMOS technologies enable ruggedized monolithic construction. The logic input is compatible with standard CMOS outputs. The output driver features a high pulse current buffer stage designed for minimum cross-conduction. The floating channel can be used to drive an N-channel power MOSFET or IGBT in the high or low side configuration which operates up to 600 volts.

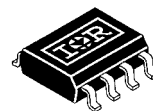
Product Summary

V_{OFFSET}	600V max.
$I_{\text{O+/-}}$	200 mA / 420 mA
V_{OUT}	10 - 20V
$t_{\text{on/off (typ.)}}$	125 & 105 ns

Packages

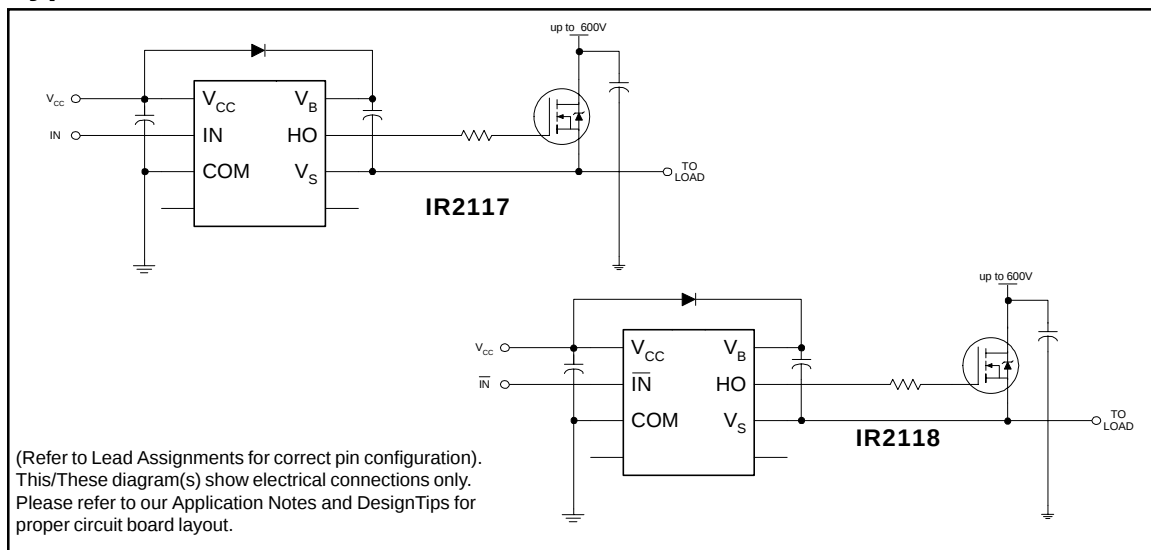


8-Lead PDIP
IR2117/IR2118



8-Lead SOIC
IR2117S/IR2118S

Typical Connection



IR2117(S)/IR2118(S) & (PbF)

International
IR Rectifier

Absolute Maximum Ratings

Absolute maximum ratings indicate sustained limits beyond which damage to the device may occur. All voltage parameters are absolute voltages referenced to COM. The thermal resistance and power dissipation ratings are measured under board mounted and still air conditions. Additional information is shown in Figures 5 through 8.

Symbol	Definition	Min.	Max.	Units
V_B	High side floating supply voltage	-0.3	625	V
V_S	High side floating supply offset voltage	$V_B - 25$	$V_B + 0.3$	
V_{HO}	High side floating output voltage	$V_S - 0.3$	$V_B + 0.3$	
V_{CC}	Logic supply voltage	-0.3	25	
V_{IN}	Logic input voltage	-0.3	$V_{CC} + 0.3$	
dV_S/dt	Allowable offset supply voltage transient (figure 2)	—	50	V/ns
P_D	Package power dissipation @ $T_A \leq +25^\circ\text{C}$ (8 lead PDIP)	—	1.0	W
	(8 lead SOIC)	—	0.625	
R_{thJA}	Thermal resistance, junction to ambient (8 lead PDIP)	—	125	$^\circ\text{C/W}$
	(8 lead SOIC)	—	200	
T_J	Junction temperature	—	150	$^\circ\text{C}$
T_S	Storage temperature	-55	150	
T_L	Lead temperature (soldering, 10 seconds)	—	300	

Recommended Operating Conditions

The input/output logic timing diagram is shown in figure 1. For proper operation the device should be used within the recommended conditions. The V_S offset rating is tested with all supplies biased at 15V differential.

Symbol	Definition	Min.	Max.	Units
V_B	High side floating supply absolute voltage	$V_S + 10$	$V_S + 20$	V
V_S	High side floating supply offset voltage	Note 1	600	
V_{HO}	High side floating output voltage	V_S	V_B	
V_{CC}	Logic supply voltage	10	20	
V_{IN}	Logic input voltage	0	V_{CC}	
T_A	Ambient temperature	-40	125	$^\circ\text{C}$

Note 1: Logic operational for V_S of -5 to +600V. Logic state held for V_S of -5V to $-V_{BS}$. (Please refer to the Design Tip DT97-3 for more details).

Dynamic Electrical Characteristics

V_{BIAS} (V_{CC} , V_{BS}) = 15V, C_L = 1000 pF and T_A = 25°C unless otherwise specified. The dynamic electrical characteristics are measured using the test circuit shown in Figure 3.

Symbol	Definition	Min.	Typ.	Max.	Units	Test Conditions
t_{on}	Turn-on propagation delay	—	125	200	ns	$V_S = 0V$
t_{off}	Turn-off propagation delay	—	105	180		$V_S = 600V$
t_r	Turn-on rise time	—	80	130		
t_f	Turn-off fall time	—	40	65		

Static Electrical Characteristics

V_{BIAS} (V_{CC} , V_{BS}) = 15V and T_A = 25°C unless otherwise specified. The V_{IN} , V_{TH} and I_{IN} parameters are referenced to COM. The V_O and I_O parameters are referenced to COM and are applicable to the respective output leads: HO or LO.

Symbol	Definition	Min.	Typ.	Max.	Units	Test Conditions
V_{IH}	input voltage - logic "1" (IR2117) logic "0" (IR2118)	9.5	—	—	V	
V_{IL}	Input voltage - logic "0" (IR2117) logic "1" (IR2118)	—	—	6.0		
V_{OH}	High level output voltage, $V_{BIAS} - V_O$	—	—	100	mV	$I_O = 0A$
V_{OL}	Low level output voltage, V_O	—	—	100		$I_O = 0A$
I_{LK}	Offset supply leakage current	—	—	50	μA	$V_B = V_S = 600V$
I_{QBS}	Quiescent V_{BS} supply current	—	50	240		$V_{IN} = 0V$ or V_{CC}
I_{QCC}	Quiescent V_{CC} Supply Current	—	70	340		$V_{IN} = 0V$ or V_{CC}
I_{IN+}	Logic "1" input bias current (IR2117)	—	20	40		$V_{IN} = V_{CC}$
	(IR2118)					$V_{IN} = 0V$
I_{IN-}	Logic "0" input bias current (IR2117)	—	—	1.0		$V_{IN} = 0V$
	(IR2118)					$V_{IN} = V_{CC}$
V_{BSUV+}	V_{BS} supply undervoltage positive going threshold	7.6	8.6	9.6	V	
V_{BSUV-}	V_{BS} supply undervoltage negative going threshold	7.2	8.2	9.2		
V_{CCUV+}	V_{CC} supply undervoltage positive going threshold	7.6	8.6	9.6		
V_{CCUV-}	V_{CC} supply undervoltage negative going threshold	7.2	8.2	9.2		
I_{O+}	Output high short circuit pulsed current	200	250	—	mA	$V_O = 0V$ $V_{IN} = \text{Logic "1"}$ $PW \leq 10 \mu s$
I_{O-}	Output low short circuit pulsed current	420	500	—		$V_O = 15V$ $V_{IN} = \text{Logic "0"}$ $PW \leq 10 \mu s$